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### **Understanding Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

#### **Details**

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	83
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-1pqq100">https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-1pqq100</a>

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## 2 40MX and 42MX FPGA Families

### 2.1 Features

The following sections list out various features of the 40MX and 42MX FPGA family devices.

#### 2.1.1 High Capacity

- Single-Chip ASIC Alternative
- 3,000 to 54,000 System Gates
- Up to 2.5 kbits Configurable Dual-Port SRAM
- Fast Wide-Decode Circuitry
- Up to 202 User-Programmable I/O Pins

#### 2.1.2 High Performance

- 5.6 ns Clock-to-Out
- 250 MHz Performance
- 5 ns Dual-Port SRAM Access
- 100 MHz FIFOs
- 7.5 ns 35-Bit Address Decode

#### 2.1.3 HiRel Features

- Commercial, Industrial, Automotive, and Military Temperature Plastic Packages
- Commercial, Military Temperature, and MIL-STD-883 Ceramic Packages
- QML Certification
- Ceramic Devices Available to DSCC SMD

#### 2.1.4 Ease of Integration

- Mixed-Voltage Operation (5.0 V or 3.3 V for core and I/Os), with PCI-Compliant I/Os
- Up to 100% Resource Utilization and 100% Pin Locking
- Deterministic, User-Controllable Timing
- Unique In-System Diagnostic and Verification Capability with Silicon Explorer II
- Low Power Consumption
- IEEE Standard 1149.1 (JTAG) Boundary Scan Testing

### 2.2 Product Profile

The following table gives the features of the products.

**Table 1 • Product profile**

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
<b>Capacity</b>						
System Gates	3,000	6,000	14,000	24,000	36,000	54,000
SRAM Bits	–	–	–	–	–	2,560
<b>Logic Modules</b>						
Sequential	–	–	348	624	954	1,230
Combinatorial	295	547	336	608	912	1,184
Decode	–	–	–	–	24	24
<b>Clock-to-Out</b>	9.5 ns	9.5 ns	5.6 ns	6.1 ns	6.1 ns	6.3 ns
<b>SRAM Modules (64x4 or 32x8)</b>						
	–	–	–	–	–	10
<b>Dedicated Flip-Flops</b>	–	–	348	624	954	1,230

## 2.4 Plastic Device Resources

**Table 2 • Plastic Device Resources**

Device	User I/Os											
	PLCC 44-Pin	PLCC 68-Pin	PLCC 84-Pin	PQFP 100-Pin	PQFP 144- Pin	PQFP 160-Pin	PQFP 208- Pin	PQFP 240-Pin	VQFP 80-Pin	VQFP 100- Pin	TQFP 176- Pin	PBGA 272- Pin
A40MX02	34	57	–	57	–	–	–	–	57	–	–	–
A40MX04	34	57	69	69	–	–	–	–	69	–	–	–
A42MX09	–	–	72	83	95	101	–	–	–	83	104	–
A42MX16	–	–	72	83	–	125	140	–	–	83	140	–
A42MX24	–	–	72	–	–	125	176	–	–	–	150	–
A42MX36	–	–	–	–	–	–	176	202	–	–	–	202

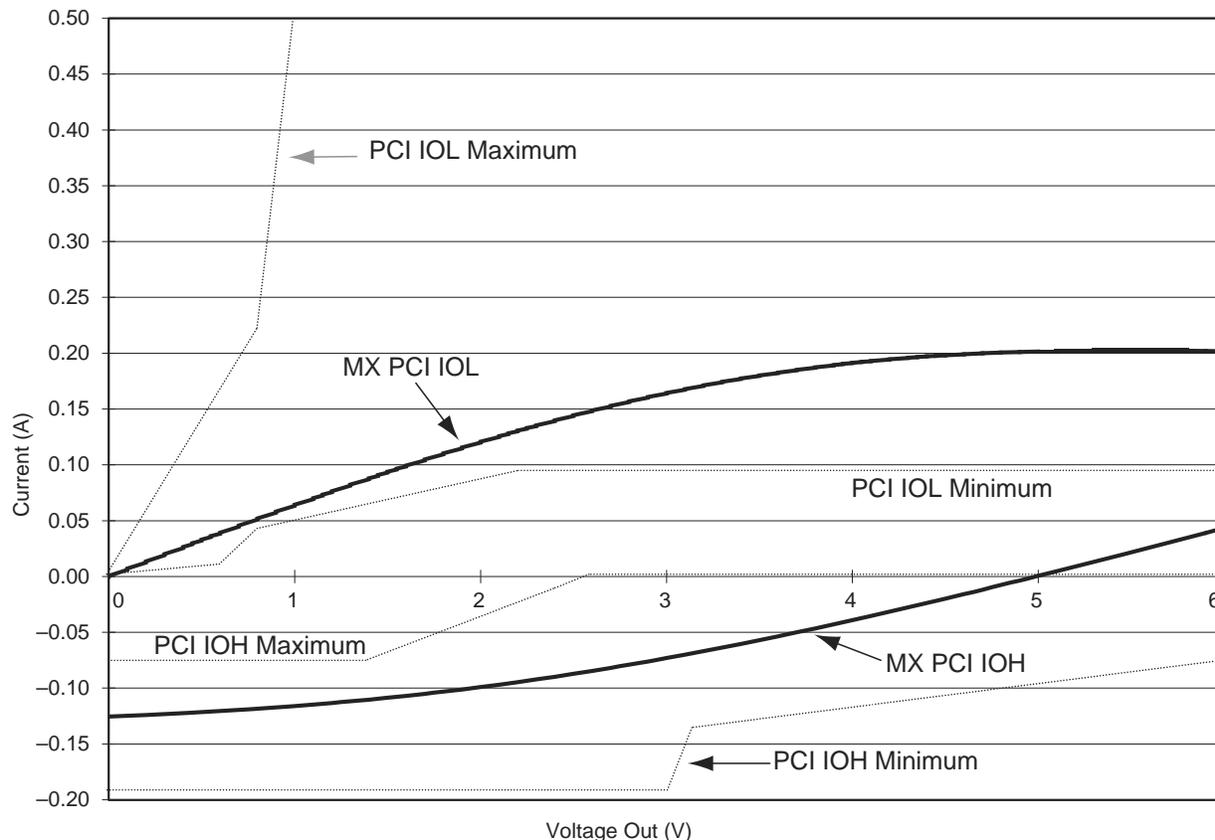
**Note: Package Definitions:** PLCC = Plastic Leaded Chip Carrier, PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, VQFP = Very Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array

## 2.5 Ceramic Device Resources

**Table 3 • Ceramic Device Resources**

Device	User I/Os			
	CPGA 132-Pin	CQFP 172-Pin	CQFP 208-Pin	CQFP 256-Pin
A42MX09	95			
A42MX16		131		
A42MX36			176	202

**Note: Package Definitions:** CQFP = Ceramic Quad Flat Pack

**Figure 16 • Typical Output Drive Characteristics (Based Upon Measured Data)**

### 3.9.4 Junction Temperature ( $T_J$ )

The temperature variable in the Designer software refers to the junction temperature, not the ambient temperature. This is an important distinction because the heat generated from dynamic power consumption is usually hotter than the ambient temperature. The following equation can be used to calculate junction temperature.

$$\text{Junction Temperature} = \Delta T + T_a(1)$$

EQ 4

where:

- $T_a$  = Ambient Temperature
- $\Delta T$  = Temperature gradient between junction (silicon) and ambient
- $\Delta T = \theta_{ja} * P$  (2)
- $P$  = Power
- $\theta_{ja}$  = Junction to ambient of package.  $\theta_{ja}$  numbers are located in Table 27, page 29.

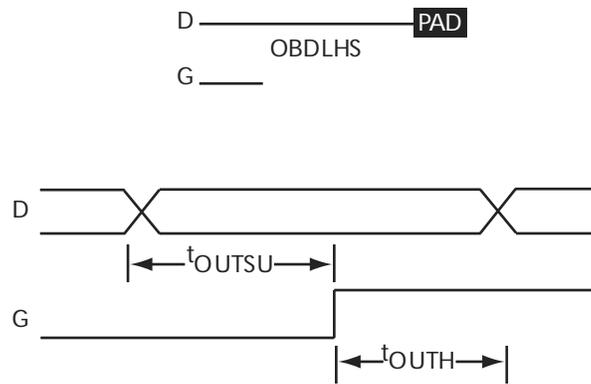
### 3.9.5 Package Thermal Characteristics

The device junction-to-case thermal characteristic is  $\theta_{jc}$ , and the junction-to-ambient air characteristic is  $\theta_{ja}$ . The thermal characteristics for  $\theta_{ja}$  are shown with two different air flow rates.

The maximum junction temperature is 150°C.

Maximum power dissipation for commercial- and industrial-grade devices is a function of  $\theta_{ja}$ .

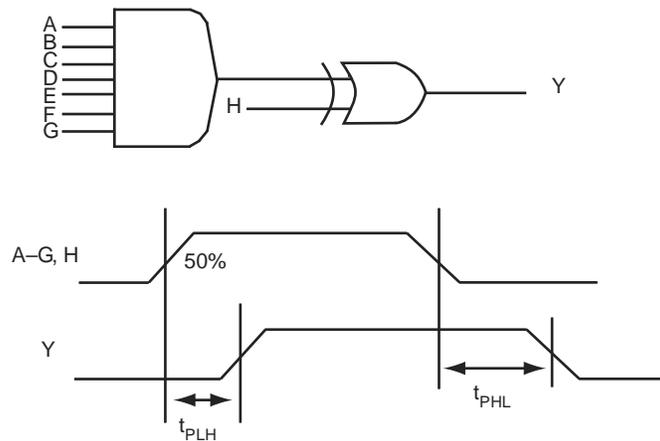
**Figure 27 • Output Buffer Latches**



### 3.10.4 Decode Module Timing

The following figure shows decode module timing.

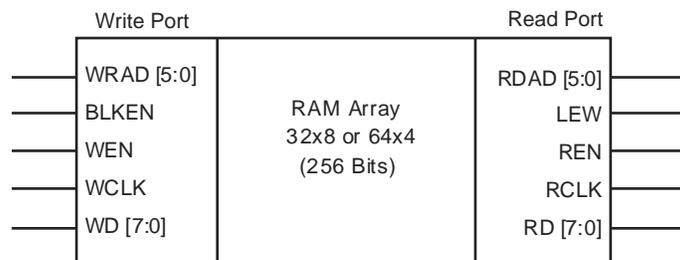
**Figure 28 • Decode Module Timing**



### 3.10.5 SRAM Timing Characteristics

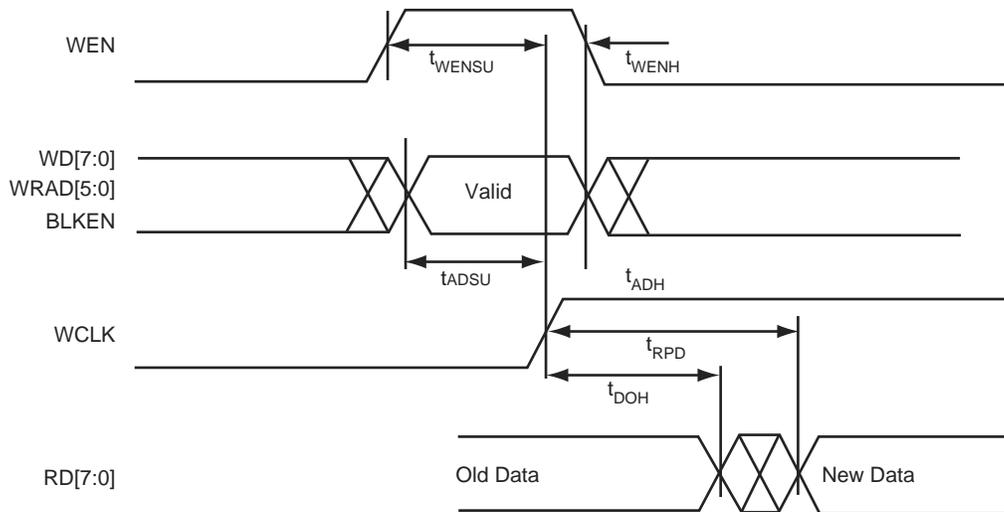
The following figure shows SRAM timing characteristics.

**Figure 29 • SRAM Timing Characteristics**



### 3.10.6 Dual-Port SRAM Timing Waveforms

The following figures show dual-port SRAM timing waveforms.

**Figure 33 • 42MX SRAM Asynchronous Read Operation—Type 2 (Write Address Controlled)**

### 3.10.7 Predictable Performance: Tight Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer routing tracks.

The MX FPGAs deliver a tight fanout delay distribution, which is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented antifuse offers a very low resistive/capacitive interconnect. The antifuses, fabricated in 0.45  $\mu\text{m}$  lithography, offer nominal levels of 100  $\Omega$  resistance and 7.0 fF capacitance per antifuse.

MX fanout distribution is also tight due to the low number of antifuses required for each interconnect path. The proprietary architecture limits the number of antifuses per path to a maximum of four, with 90 percent of interconnects using only two antifuses.

## 3.11 Timing Characteristics

Device timing characteristics fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all MX devices. Internal routing delays are device-dependent; actual delays are not determined until after place-and-route of the user's design is complete. Delay values may then be determined by using the Designer software utility or by performing simulation with post-layout delays.

### 3.11.1 Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing critical paths. Critical nets are determined by net property assignment in Microsemi's Designer software prior to placement and routing. Up to 6% of the nets in a design may be designated as critical.

### 3.11.2 Long Tracks

Some nets in the design use long tracks, which are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections, which increase capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks add

**Table 35 • A40MX02 Timing Characteristics (Nominal 3.3 V Operation) (continued)**  
(Worst-Case Commercial Conditions, VCC = 3.0 V, T<sub>J</sub> = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>RD1</sub>	FO = 1 Routing Delay		2.0	2.2	2.5	3.0	4.2	ns				
t <sub>RD2</sub>	FO = 2 Routing Delay		2.7	3.1	3.5	4.1	5.7	ns				
t <sub>RD3</sub>	FO = 3 Routing Delay		3.4	3.9	4.4	5.2	7.3	ns				
t <sub>RD4</sub>	FO = 4 Routing Delay		4.2	4.8	5.4	6.3	8.9	ns				
t <sub>RD8</sub>	FO = 8 Routing Delay		7.1	8.2	9.2	10.9	15.2	ns				
<b>Logic Module Sequential Timing<sup>2</sup></b>												
t <sub>SUD</sub>	Flip-Flop (Latch) Data Input Set-Up		4.3	4.9	5.6	6.6	9.2	ns				
t <sub>HD</sub> <sup>3</sup>	Flip-Flop (Latch) Data Input Hold		0.0	0.0	0.0	0.0	0.0	ns				
t <sub>SUENA</sub>	Flip-Flop (Latch) Enable Set-Up		4.3	4.9	5.6	6.6	9.2	ns				
t <sub>HENA</sub>	Flip-Flop (Latch) Enable Hold		0.0	0.0	0.0	0.0	0.0	ns				
t <sub>WCLKA</sub>	Flip-Flop (Latch) Clock Active Pulse Width		4.6	5.3	6.0	7.0	9.8	ns				
t <sub>WASYN</sub>	Flip-Flop (Latch) Asynchronous Pulse Width		4.6	5.3	6.0	7.0	9.8	ns				
t <sub>A</sub>	Flip-Flop Clock Input Period		6.8	7.8	8.9	10.4	14.6	ns				
f <sub>MAX</sub>	Flip-Flop (Latch) Clock Frequency (FO = 128)		109	101	92	80	48	MHz				
<b>Input Module Propagation Delays</b>												
t <sub>INYH</sub>	Pad-to-Y HIGH		1.0	1.1	1.3	1.5	2.1	ns				
t <sub>INYL</sub>	Pad-to-Y LOW		0.9	1.0	1.1	1.3	1.9	ns				
<b>Input Module Predicted Routing Delays<sup>1</sup></b>												
t <sub>IRD1</sub>	FO = 1 Routing Delay		2.9	3.4	3.8	4.5	6.3	ns				
t <sub>IRD2</sub>	FO = 2 Routing Delay		3.6	4.2	4.8	5.6	7.8	ns				
t <sub>IRD3</sub>	FO = 3 Routing Delay		4.4	5.0	5.7	6.7	9.4	ns				
t <sub>IRD4</sub>	FO = 4 Routing Delay		5.1	5.9	6.7	7.8	11.0	ns				
t <sub>IRD8</sub>	FO = 8 Routing Delay		8.0	9.26	10.5	12.6	17.3	ns				
<b>Global Clock Network</b>												
t <sub>CKH</sub>	Input LOW to HIGH	FO = 16	6.4	7.4	8.3	9.8	13.7	ns				
		FO = 128	6.4	7.4	8.3	9.8	13.7					
t <sub>CKL</sub>	Input HIGH to LOW	FO = 16	6.7	7.8	8.8	10.4	14.5	ns				
		FO = 128	6.7	7.8	8.8	10.4	14.5					
t <sub>PWH</sub>	Minimum Pulse Width HIGH	FO = 16	3.1	3.6	4.1	4.8	6.7	ns				
		FO = 128	3.3	3.8	4.3	5.1	7.1					
t <sub>PWL</sub>	Minimum Pulse Width LOW	FO = 16	3.1	3.6	4.1	4.8	6.7	ns				
		FO = 128	3.3	3.8	4.3	5.1	7.1					
t <sub>CKSW</sub>	Maximum Skew	FO = 16	0.6	0.6	0.7	0.8	1.2	ns				
		FO = 128	0.8	0.9	1.0	1.2	1.6					

**Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T<sub>J</sub> = 70°C)**

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>WCLKA</sub> Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t <sub>WASYN</sub> Flip-Flop (Latch) Asynchronous Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t <sub>A</sub> Flip-Flop Clock Input Period	6.8		7.8		8.9		10.4		14.6		ns
f <sub>MAX</sub> Flip-Flop (Latch) Clock Frequency (FO = 128)		109		101		92		80		48	MHz
<b>Input Module Propagation Delays</b>											
t <sub>INYH</sub> Pad-to-Y HIGH		1.0		1.1		1.3		1.5		2.1	ns
t <sub>INYL</sub> Pad-to-Y LOW		0.9		1.0		1.1		1.3		1.9	ns

**Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T<sub>J</sub> = 70°C)**

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
<b>CMOS Output Module Timing<sup>5</sup></b>											
t <sub>DLH</sub>	Data-to-Pad HIGH	3.2	3.6	4.0	4.7	6.6	ns				
t <sub>DHL</sub>	Data-to-Pad LOW	2.5	2.7	3.1	3.6	5.1	ns				
t <sub>ENZH</sub>	Enable Pad Z to HIGH	2.7	3.0	3.4	4.0	5.6	ns				
t <sub>ENZL</sub>	Enable Pad Z to LOW	3.0	3.3	3.8	4.4	6.2	ns				
t <sub>ENHZ</sub>	Enable Pad HIGH to Z	5.4	6.0	6.8	8.0	11.2	ns				
t <sub>ENLZ</sub>	Enable Pad LOW to Z	5.0	5.6	6.3	7.4	10.4	ns				
t <sub>GLH</sub>	G-to-Pad HIGH	5.1	5.6	6.4	7.5	10.5	ns				
t <sub>GHL</sub>	G-to-Pad LOW	5.1	5.6	6.4	7.5	10.5	ns				
t <sub>LCO</sub>	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading	5.7	6.3	7.1	8.4	11.9	ns				
t <sub>ACO</sub>	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading	8.0	8.9	10.1	11.9	16.7	ns				
d <sub>TLH</sub>	Capacitive Loading, LOW to HIGH	0.03	0.03	0.03	0.04	0.06	ns/pF				

1. For dual-module macros, use t<sub>PD1</sub> + t<sub>RD1</sub> + t<sub>PDn</sub>, t<sub>CO</sub> + t<sub>RD1</sub> + t<sub>PDn</sub>, or t<sub>PD1</sub> + t<sub>RD1</sub> + t<sub>SUD</sub>, point and position whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. *Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.*
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading

**Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T<sub>J</sub> = 70°C)**

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
<b>Logic Module Propagation Delays<sup>1</sup></b>											
t <sub>PD1</sub>	Single Module	1.9	2.1	2.4	2.8	4.0	ns				
t <sub>CO</sub>	Sequential Clock-to-Q	2.0	2.2	2.5	3.0	4.2	ns				
t <sub>GO</sub>	Latch G-to-Q	1.9	2.1	2.4	2.8	4.0	ns				
t <sub>RS</sub>	Flip-Flop (Latch) Reset-to-Q	2.2	2.4	2.8	3.3	4.6	ns				
<b>Logic Module Predicted Routing Delays<sup>2</sup></b>											
t <sub>RD1</sub>	FO = 1 Routing Delay	1.1	1.2	1.4	1.6	2.3	ns				
t <sub>RD2</sub>	FO = 2 Routing Delay	1.5	1.6	1.8	2.1	3.0	ns				
t <sub>RD3</sub>	FO = 3 Routing Delay	1.8	2.0	2.3	2.7	3.8	ns				
t <sub>RD4</sub>	FO = 4 Routing Delay	2.2	2.4	2.7	3.2	4.5	ns				
t <sub>RD8</sub>	FO = 8 Routing Delay	3.6	4.0	4.5	5.3	7.5	ns				

**Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T<sub>J</sub> = 70°C)**

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
<b>TTL Output Module Timing<sup>5</sup> (Continued)</b>											
t <sub>ENLZ</sub>	Enable Pad LOW to Z		4.9	5.5	6.2	7.3	10.2	ns			
t <sub>GLH</sub>	G-to-Pad HIGH		2.9	3.3	3.7	4.4	6.1	ns			
t <sub>GHL</sub>	G-to-Pad LOW		2.9	3.3	3.7	4.4	6.1	ns			
t <sub>LSU</sub>	I/O Latch Output Set-Up		0.5	0.5	0.6	0.7	1.0	ns			
t <sub>LH</sub>	I/O Latch Output Hold		0.0	0.0	0.0	0.0	0.0	ns			
t <sub>LCO</sub>	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7	6.3	7.1	8.4	11.8	ns			
t <sub>ACO</sub>	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8	8.6	9.8	11.5	16.1	ns			
d <sub>TLH</sub>	Capacitive Loading, LOW to HIGH		0.07	0.08	0.09	0.10	0.14	ns/pF			
d <sub>THL</sub>	Capacitive Loading, HIGH to LOW		0.07	0.08	0.09	0.10	0.14	ns/pF			

**Table 50 • PQ 100**

<b>PQ100</b>				
<b>Pin Number</b>	<b>A40MX02 Function</b>	<b>A40MX04 Function</b>	<b>A42MX09 Function</b>	<b>A42MX16 Function</b>
93	VCC	VCC	I/O	I/O
94	VCC	VCC	PRB, I/O	PRB, I/O
95	NC	I/O	I/O	I/O
96	NC	I/O	GND	GND
97	NC	I/O	I/O	I/O
98	SDI, I/O	SDI, I/O	I/O	I/O
99	DCLK, I/O	DCLK, I/O	I/O	I/O
100	PRA, I/O	PRA, I/O	I/O	I/O

**Table 51 • PQ144**

<b>PQ144</b>	
<b>Pin Number</b>	<b>A42MX09 Function</b>
117	GNDI
118	NC
119	I/O
120	I/O
121	I/O
122	I/O
123	PROBA
124	I/O
125	CLKA
126	VCC
127	VCCI
128	NC
129	I/O
130	CLKB
131	I/O
132	PROBB
133	I/O
134	I/O
135	I/O
136	GND
137	GNDI
138	NC
139	I/O
140	I/O
141	I/O
142	I/O
143	I/O
144	DCLK

**Table 52 • PQ160**

<b>PQ160</b>			
<b>Pin Number</b>	<b>A42MX09 Function</b>	<b>A42MX16 Function</b>	<b>A42MX24 Function</b>
21	CLKA, I/O	CLKA, I/O	CLKA, I/O
22	I/O	I/O	I/O
23	PRA, I/O	PRA, I/O	PRA, I/O
24	NC	I/O	WD, I/O
25	I/O	I/O	WD, I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	NC	I/O	I/O
29	I/O	I/O	WD, I/O
30	GND	GND	GND
31	NC	I/O	WD, I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	NC	VCCI	VCCI
36	I/O	I/O	WD, I/O
37	I/O	I/O	WD, I/O
38	SDI, I/O	SDI, I/O	SDI, I/O
39	I/O	I/O	I/O
40	GND	GND	GND
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	GND	GND	GND
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	GND	GND	GND
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	NC	I/O	I/O
53	I/O	I/O	I/O
54	NC	VCCA	VCCA
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	VCCA	VCCA	VCCA

**Table 54 • PQ240**

<b>PQ240</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
52	VCCI
53	I/O
54	WD, I/O
55	WD, I/O
56	I/O
57	SDI, I/O
58	I/O
59	VCCA
60	GND
61	GND
62	I/O
63	I/O
64	I/O
65	I/O
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	VCCI
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	VCCA
86	I/O
87	I/O
88	VCCA

**Table 55 • VQ80**

<b>VQ80</b>		
<b>Pin Number</b>	<b>A40MX02 Function</b>	<b>A40MX04 Function</b>
13	VCC	VCC
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	NC	I/O
18	NC	I/O
19	NC	I/O
20	VCC	VCC
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	GND	GND
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	I/O	I/O
33	VCC	VCC
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	I/O	I/O
39	I/O	I/O
40	I/O	I/O
41	NC	I/O
42	NC	I/O
43	NC	I/O
44	I/O	I/O
45	I/O	I/O
46	I/O	I/O
47	GND	GND
48	I/O	I/O

**Table 57 • TQ176**

<b>TQ176</b>			
<b>Pin Number</b>	<b>A42MX09 Function</b>	<b>A42MX16 Function</b>	<b>A42MX24 Function</b>
47	I/O	I/O	TDI, I/O
48	I/O	I/O	I/O
49	I/O	I/O	WD, I/O
50	I/O	I/O	WD, I/O
51	I/O	I/O	I/O
52	NC	VCCI	VCCI
53	I/O	I/O	I/O
54	NC	I/O	I/O
55	NC	I/O	WD, I/O
56	I/O	I/O	WD, I/O
57	NC	NC	I/O
58	I/O	I/O	I/O
59	I/O	I/O	WD, I/O
60	I/O	I/O	WD, I/O
61	NC	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	NC	I/O	I/O
65	I/O	I/O	I/O
66	NC	I/O	I/O
67	GND	GND	GND
68	VCCA	VCCA	VCCA
69	I/O	I/O	WD, I/O
70	I/O	I/O	WD, I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	NC	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	NC	NC	WD, I/O
78	NC	I/O	WD, I/O
79	I/O	I/O	I/O
80	NC	I/O	I/O
81	I/O	I/O	I/O
82	NC	VCCI	VCCI
83	I/O	I/O	I/O

**Table 59 • CQ256**

<b>CQ256</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
59	I/O
60	VCCA
61	GND
62	GND
63	NC
64	NC
65	NC
66	I/O
67	SDO, TDO, I/O
68	I/O
69	WD, I/O
70	WD, I/O
71	I/O
72	VCCI
73	I/O
74	I/O
75	I/O
76	WD, I/O
77	GND
78	WD, I/O
79	I/O
80	QCLKB, I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	I/O
86	I/O
87	WD, I/O
88	WD, I/O
89	I/O
90	I/O
91	I/O
92	I/O
93	I/O
94	I/O
95	VCCI

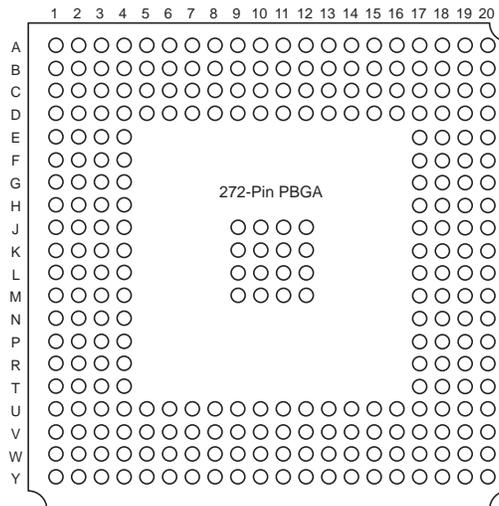
**Table 59 • CQ256**

<b>CQ256</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
207	I/O
208	I/O
209	QCLKC, I/O
210	I/O
211	WD, I/O
212	WD, I/O
213	I/O
214	I/O
215	WD, I/O
216	WD, I/O
217	I/O
218	PRB, I/O
219	I/O
220	CLKB, I/O
221	I/O
222	GND
223	GND
224	VCCA
225	VCCI
226	I/O
227	CLKA, I/O
228	I/O
229	PRA, I/O
230	I/O
231	I/O
232	WD, I/O
233	WD, I/O
234	I/O
235	I/O
236	I/O
237	I/O
238	I/O
239	I/O
240	QCLKD, I/O
241	I/O
242	WD, I/O
243	GND

**Table 59 • CQ256**

<b>CQ256</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
244	WD, I/O
245	I/O
246	I/O
247	I/O
248	VCCI
249	I/O
250	WD, I/O
251	WD, I/O
252	I/O
253	SDI, I/O
254	I/O
255	GND
256	NC

**Figure 51 • BG272**



**Table 60 • BG272**

<b>BG272</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
A1	GND
A2	GND
A3	I/O
A4	WD, I/O
A5	I/O

**Table 60 • BG272**

<b>BG272</b>	
<b>Pin Number</b>	<b>A42MX36 Function</b>
A6	I/O
A7	WD, I/O
A8	WD, I/O
A9	I/O
A10	I/O
A11	CLKA
A12	I/O
A13	I/O
A14	I/O
A15	I/O
A16	WD, I/O
A17	I/O
A18	I/O
A19	GND
A20	GND
B1	GND
B2	GND
B3	DCLK, I/O
B4	I/O
B5	I/O
B6	I/O
B7	WD, I/O
B8	I/O
B9	PRB, I/O
B10	I/O
B11	I/O
B12	WD, I/O
B13	I/O
B14	I/O
B15	WD, I/O
B16	I/O
B17	WD, I/O
B18	I/O
B19	GND
B20	GND
C1	I/O
C2	MODE